

Search Notes

Application/Control No.

10/653,921

Examiner

Erin D. Chiem

Applicant(s)/Patent under
Reexamination

PICKRELL ET AL.

Art Unit

2883

SEARCHED

Class	Subclass	Date	Examiner
385	12	3/3/2005	EDC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
385/12 and (monocrystalline mono adj crystalline)	3/3/2005	EDC
thermal near coefficient near expansion same (differ\$6 maximi\$6) same substrate same (waveguide fib\$3) and (sensor detector)	3/3/2005	EDC
optic\$4 near (sensor detector) and reflect\$6 near diaphragm and crystal\$8	3/3/2005	EDC
Forward and Backward citation search	3/3/2005	EDC